www.SeCosGmbH.com

Headquarter Address:
8F.No.33, Lane 155, Sec.3, Bei-Shen Rd.,
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Product/Process Change Notification

PCN#	Effective Date	Issue Date
2015-08-10C-01	2016/2/10	2015/8/10

PCN Classification	Product Category
Major	SST3585S

Subject
Change assembly factory

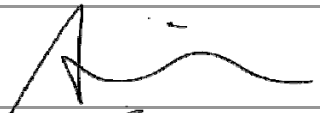
Affected Product(s)
SST3585S

Description of Change(s)
Original assembly factory EOL, thus Change assembly factory.

Content of Change(s)
Assembly vendor

Impact(s)
N/A

Attachment(s)
Reliability Teat Report.

Approval		
Issue by	Alice Lai	e-mail: alice@secosgmbh.com
Development Engineer		Alice Lai
QA Manager		Peter Yang
General Manger		Mathew Liu

For more information, please contact us directly or visit our website http://www.secosgmbh.com

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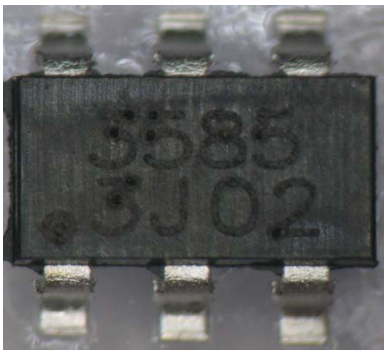
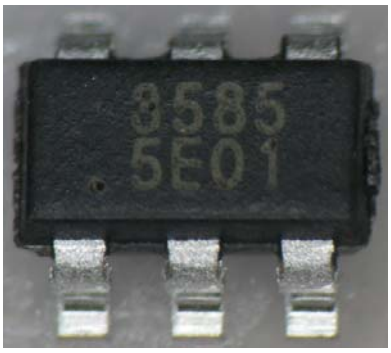
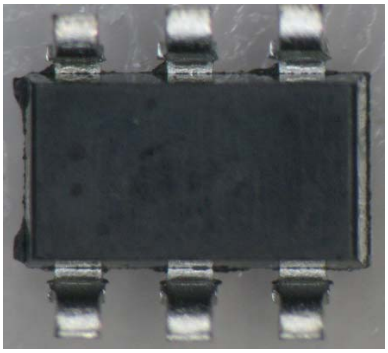
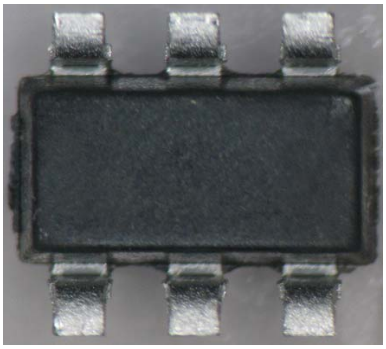
Exterior comparison Chart	
Original	New
	
Top View	Top View
	
Lateral View	Lateral View

SeCoS Corporation

Reliability Testing Summary Report

Date: 2015/07/24 Document No.: SI15 -07- 13

Test Item	P/N	Test Condition	(LTPD)	Sample Numbers	Allow Fall Numbers	Fall Numbers	Result
HTRB High Temp Reverse Bias	SST3585S	150 ± 5℃, 80%VR, T = 1000hrs		77	0	0	ACC
HTSL High Temperature Storage Life	SST3585S	150℃, T = 1000 hrs		77	0	0	ACC
PCT Pressure Cooker Test	SST3585S	121℃, 29.7PSIG, 168 hrs		77	0	0	ACC
TCT Temperature Cycle Test	SST3585S	-55℃/30min, 150℃/30min, For 1000 Cycle		77	0	0	ACC
THT High Temperature High Humidity Test	SST3585S	85 ± 2℃, RH=85±5%, 1000 hrs		77	0	0	ACC
H3TRB High Temper High Humidity Reverse Bies Test	SST3585S	85 ± 2℃, RH=85±5%, 1000 hrs		77	0	0	ACC
Solderability	SST3585S	245 ± 5℃, 5Sec the inspected area of each lead must have 95% solder coverage minimum		10	0	0	ACC

Judgment:

■ **qualified** □ **unqualified**

Testing Start Date: 2015.06.01 Testing End Date: 2015.07.24

Tester: King Huang Approval: Peter Yang

SeCoS Corporation

Electrical Test Data

Report No : T150724-011
Part No : SST3585S
Test Equipment: JUNO Test System DTS-1000
Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)
Test Condition: 25℃
Test Date: 2015.06.01
Test Standard : Specifications
Operator: Leo Hsia

Test Result: PASS

No	N-Channel			P-Channel		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
1	0.044	0.635	61.41	-0.037	-0.616	61.19
2	0.067	0.638	61.90	-0.029	-0.646	60.12
3	0.044	0.659	61.71	-0.062	-0.616	60.68
4	0.056	0.639	60.64	-0.029	-0.622	60.64
5	0.046	0.616	60.36	-0.050	-0.615	60.12
6	0.051	0.650	60.94	-0.027	-0.638	61.95
7	0.062	0.637	62.23	-0.056	-0.642	62.14
8	0.041	0.656	60.24	-0.051	-0.614	60.48
9	0.028	0.615	60.73	-0.042	-0.639	60.74
10	0.059	0.650	60.66	-0.067	-0.654	61.05
11	0.022	0.624	60.91	-0.024	-0.610	61.47
12	0.057	0.608	62.02	-0.036	-0.648	62.17
13	0.023	0.659	61.89	-0.032	-0.662	61.92
14	0.041	0.625	61.25	-0.063	-0.612	60.16
15	0.029	0.612	62.30	-0.025	-0.613	60.60
16	0.041	0.663	60.58	-0.057	-0.658	60.09
17	0.056	0.653	60.63	-0.033	-0.605	62.25
18	0.024	0.624	60.12	-0.041	-0.611	61.83
19	0.036	0.625	60.62	-0.049	-0.604	61.79
20	0.064	0.643	60.95	-0.030	-0.615	61.19
21	0.028	0.618	61.13	-0.057	-0.628	61.44
22	0.056	0.660	60.05	-0.022	-0.661	60.44
23	0.060	0.651	62.22	-0.028	-0.631	61.97
24	0.053	0.626	60.83	-0.041	-0.658	60.84
25	0.061	0.622	61.25	-0.056	-0.633	62.12
26	0.066	0.627	60.55	-0.026	-0.631	60.47
27	0.022	0.620	61.74	-0.036	-0.662	60.23

SeCoS Corporation

Electrical Test Data

Report No : T150724-011
Part No : SST3585S
Test Equipment: JUNO Test System DTS-1000
Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)
Test Condition: 25℃
Test Date: 2015.06.01
Test Standard : Specifications
Operator: Leo Hsia

Test Result: PASS

No	N-Channel			P-Channel		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
28	0.040	0.661	60.21	-0.027	-0.618	61.83
29	0.023	0.632	60.11	-0.026	-0.616	60.60
30	0.033	0.632	61.16	-0.067	-0.637	61.81
31	0.052	0.635	60.16	-0.022	-0.662	62.13
32	0.027	0.646	61.68	-0.025	-0.652	60.32
33	0.025	0.626	62.27	-0.023	-0.615	60.31
34	0.040	0.644	62.27	-0.045	-0.608	61.18
35	0.062	0.620	60.63	-0.061	-0.618	61.12
36	0.056	0.660	60.91	-0.025	-0.656	60.11
37	0.027	0.612	62.17	-0.026	-0.609	60.28
38	0.047	0.631	60.73	-0.051	-0.619	60.59
39	0.034	0.652	61.21	-0.041	-0.629	61.12
40	0.061	0.641	62.07	-0.024	-0.653	61.66
41	0.061	0.627	60.29	-0.028	-0.629	61.52
42	0.037	0.625	61.29	-0.058	-0.652	60.89
43	0.030	0.658	60.43	-0.037	-0.624	61.92
44	0.046	0.623	61.42	-0.024	-0.615	61.12
45	0.058	0.621	60.21	-0.032	-0.612	60.89
46	0.036	0.616	61.77	-0.027	-0.607	61.40
47	0.030	0.646	61.03	-0.039	-0.614	60.99
48	0.043	0.606	61.29	-0.061	-0.663	61.86
49	0.047	0.639	60.12	-0.051	-0.647	61.47
50	0.033	0.654	61.73	-0.031	-0.628	60.36
51	0.041	0.635	60.19	-0.054	-0.631	60.39
52	0.042	0.620	62.19	-0.043	-0.633	60.72
53	0.033	0.623	60.88	-0.044	-0.656	60.04
54	0.047	0.655	62.35	-0.059	-0.643	61.39

SeCoS Corporation

Electrical Test Data

Report No : T150724-011
Part No : SST3585S
Test Equipment: JUNO Test System DTS-1000
Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)
Test Condition: 25℃
Test Date: 2015.06.01
Test Standard : Specifications
Operator: Leo Hsia

Test Result: PASS

No	N-Channel			P-Channel		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
55	0.049	0.607	60.27	-0.028	-0.646	62.20
56	0.024	0.659	61.75	-0.037	-0.638	61.30
57	0.025	0.630	60.54	-0.040	-0.644	61.27
58	0.033	0.610	61.78	-0.049	-0.605	62.21
59	0.067	0.638	62.05	-0.064	-0.631	60.22
60	0.056	0.658	60.85	-0.052	-0.638	62.01
61	0.049	0.647	61.35	-0.043	-0.658	61.69
62	0.024	0.608	60.44	-0.044	-0.653	60.97
63	0.028	0.609	60.96	-0.041	-0.655	60.78
64	0.063	0.625	61.38	-0.041	-0.620	60.15
65	0.023	0.645	62.06	-0.048	-0.610	62.26
66	0.039	0.611	60.82	-0.039	-0.656	61.25
67	0.031	0.659	60.31	-0.036	-0.655	61.94
68	0.032	0.658	62.40	-0.058	-0.623	60.36
69	0.056	0.605	61.99	-0.022	-0.627	60.91
70	0.033	0.640	60.41	-0.054	-0.644	60.71
71	0.029	0.618	60.51	-0.032	-0.621	60.35
72	0.056	0.663	62.36	-0.047	-0.655	60.89
73	0.038	0.655	61.98	-0.028	-0.615	62.16
74	0.041	0.631	60.26	-0.043	-0.607	61.63
75	0.024	0.631	60.07	-0.056	-0.618	60.60
76	0.046	0.639	61.01	-0.042	-0.647	60.55
77	0.040	0.611	61.27	-0.045	-0.662	62.10

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T150724-011

Part No : SST3585S

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 150 ± 5℃, 80%VR, T = 1000 hrs

Test Date: 2015.06.01 ~ 2015.07.14

Test Standard : JESD22 STANDARD Method-A108

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
1	0.002	0.783	31.61	0.007	0.779	49.30	-0.000	-0.673	78.32	-0.001	-0.682	77.54
2	0.003	0.795	44.86	0.001	0.802	36.92	-0.000	-0.669	76.99	-0.002	-0.666	77.69
3	0.004	0.821	29.54	0.000	0.812	45.48	-0.001	-0.686	73.65	-0.001	-0.664	76.59
4	0.004	0.822	32.19	0.005	0.784	42.81	-0.002	-0.668	77.56	-0.000	-0.711	73.75
5	0.001	0.807	36.05	0.001	0.826	30.82	-0.002	-0.709	76.38	-0.003	-0.749	75.29
6	0.004	0.818	46.48	0.003	0.780	45.50	-0.000	-0.672	76.23	-0.003	-0.732	73.97
7	0.006	0.811	41.57	0.001	0.800	42.60	-0.002	-0.744	77.44	-0.002	-0.668	75.31
8	0.001	0.798	42.03	0.004	0.811	34.58	-0.003	-0.758	76.06	-0.002	-0.747	78.50
9	0.004	0.826	50.19	0.002	0.793	32.43	-0.001	-0.681	75.15	-0.001	-0.735	74.93
10	0.001	0.796	41.39	0.007	0.785	49.32	-0.000	-0.758	76.32	-0.002	-0.686	77.27
11	0.004	0.800	46.72	0.001	0.799	50.79	-0.003	-0.677	77.68	-0.000	-0.729	75.01
12	0.005	0.797	38.96	0.002	0.793	48.84	-0.002	-0.754	75.29	-0.002	-0.732	78.67
13	0.005	0.789	46.98	0.000	0.779	41.29	-0.000	-0.663	74.23	-0.003	-0.697	76.65
14	0.003	0.826	33.94	0.006	0.798	29.48	-0.002	-0.714	77.73	-0.003	-0.716	75.46
15	0.001	0.804	47.57	0.004	0.813	31.21	-0.001	-0.760	76.70	-0.002	-0.693	77.68
16	0.005	0.794	40.38	0.001	0.786	43.98	-0.002	-0.707	74.68	-0.002	-0.739	73.84
17	0.006	0.794	45.48	0.004	0.825	36.91	-0.002	-0.708	75.26	-0.002	-0.710	78.13
18	0.005	0.803	50.87	0.004	0.816	36.23	-0.001	-0.664	77.55	-0.001	-0.737	74.68
19	0.005	0.792	40.35	0.002	0.785	45.43	-0.001	-0.700	73.83	-0.001	-0.755	76.17
20	0.002	0.809	47.13	0.006	0.795	29.46	-0.000	-0.755	77.21	-0.003	-0.700	78.21
21	0.002	0.827	50.95	0.006	0.813	33.70	-0.001	-0.693	75.68	-0.000	-0.712	76.12
22	0.003	0.807	39.69	0.006	0.801	50.54	-0.001	-0.697	78.62	-0.002	-0.711	75.63
23	0.006	0.815	48.74	0.001	0.810	29.09	-0.000	-0.665	78.49	-0.001	-0.714	74.74
24	0.006	0.807	49.82	0.007	0.791	30.90	-0.002	-0.662	74.83	-0.002	-0.743	78.08
25	0.004	0.792	45.28	0.007	0.829	31.72	-0.003	-0.748	75.71	-0.002	-0.759	74.07
26	0.002	0.814	41.86	0.002	0.799	36.55	-0.003	-0.713	77.36	-0.001	-0.683	75.06
27	0.003	0.789	51.92	0.003	0.798	28.95	-0.003	-0.755	77.48	-0.001	-0.731	74.84

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T150724-011

Part No : SST3585S

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 150 ± 5℃, 80%VR, T = 1000 hrs

Test Date: 2015.06.01 ~ 2015.07.14

Test Standard : JESD22 STANDARD Method-A108

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
28	0.001	0.826	43.51	0.001	0.829	40.76	-0.001	-0.742	76.55	-0.001	-0.683	76.48
29	0.000	0.808	43.47	0.003	0.826	51.77	-0.003	-0.664	76.87	-0.002	-0.718	76.33
30	0.002	0.785	51.66	0.006	0.798	41.75	-0.003	-0.719	75.05	-0.003	-0.728	74.77
31	0.006	0.814	51.71	0.007	0.783	37.28	-0.000	-0.724	75.79	-0.002	-0.667	76.26
32	0.002	0.785	31.95	0.000	0.799	28.75	-0.000	-0.664	77.52	-0.001	-0.660	78.24
33	0.001	0.816	45.80	0.002	0.800	48.68	-0.002	-0.704	75.86	-0.001	-0.707	78.65
34	0.001	0.784	40.69	0.005	0.822	47.27	-0.002	-0.665	75.33	-0.003	-0.672	77.36
35	0.004	0.812	50.77	0.005	0.782	51.46	-0.002	-0.716	75.28	-0.002	-0.701	73.86
36	0.003	0.792	30.02	0.002	0.796	37.14	-0.002	-0.716	74.82	-0.003	-0.724	77.67
37	0.002	0.788	45.39	0.005	0.828	40.61	-0.001	-0.692	77.06	-0.002	-0.686	77.03
38	0.006	0.826	33.27	0.000	0.816	33.25	-0.003	-0.756	74.18	-0.002	-0.759	76.82
39	0.007	0.799	35.06	0.003	0.782	33.49	-0.001	-0.761	73.82	-0.002	-0.699	74.92
40	0.002	0.781	48.79	0.006	0.818	49.31	-0.001	-0.747	78.51	-0.001	-0.762	75.68
41	0.002	0.823	35.22	0.000	0.810	31.95	-0.003	-0.715	73.74	-0.002	-0.672	74.72
42	0.000	0.780	34.25	0.002	0.811	46.91	-0.002	-0.665	76.84	-0.002	-0.678	74.75
43	0.006	0.830	49.36	0.001	0.807	44.53	-0.002	-0.757	75.53	-0.000	-0.763	74.67
44	0.004	0.781	48.77	0.005	0.794	43.10	-0.001	-0.662	74.82	-0.003	-0.764	78.08
45	0.001	0.811	51.86	0.005	0.783	33.76	-0.002	-0.672	73.92	-0.002	-0.681	73.61
46	0.007	0.803	45.83	0.007	0.813	39.87	-0.002	-0.745	77.42	-0.001	-0.761	78.13
47	0.005	0.810	40.21	0.005	0.782	45.68	-0.001	-0.704	76.21	-0.001	-0.714	78.58
48	0.001	0.807	45.70	0.005	0.802	31.71	-0.002	-0.679	74.38	-0.001	-0.686	77.44
49	0.000	0.799	32.14	0.003	0.780	30.80	-0.002	-0.707	75.81	-0.003	-0.735	75.84
50	0.005	0.830	42.26	0.005	0.786	36.27	-0.001	-0.721	75.07	-0.002	-0.689	74.39
51	0.001	0.827	38.57	0.004	0.780	39.65	-0.003	-0.733	76.83	-0.001	-0.732	77.51
52	0.003	0.800	47.50	0.004	0.798	44.55	-0.002	-0.681	73.72	-0.001	-0.743	73.97
53	0.004	0.796	39.65	0.002	0.780	45.51	-0.001	-0.698	77.31	-0.002	-0.726	74.75
54	0.004	0.797	39.15	0.004	0.811	42.52	-0.003	-0.677	75.91	-0.001	-0.676	74.84

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T150724-011

Part No : SST3585S

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 150 ± 5℃, 80%VR, T = 1000 hrs

Test Date: 2015.06.01 ~ 2015.07.14

Test Standard : JESD22 STANDARD Method-A108

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
55	0.001	0.817	37.80	0.005	0.783	44.88	-0.003	-0.692	76.90	-0.003	-0.701	78.35
56	0.004	0.817	35.10	0.001	0.804	45.29	-0.001	-0.691	74.39	-0.002	-0.710	74.12
57	0.007	0.820	50.91	0.002	0.788	48.78	-0.003	-0.675	76.78	-0.003	-0.676	75.88
58	0.004	0.811	42.28	0.002	0.813	34.65	-0.001	-0.741	78.16	-0.001	-0.674	75.71
59	0.005	0.797	35.34	0.002	0.792	43.98	-0.001	-0.724	74.35	-0.001	-0.694	76.89
60	0.003	0.792	38.38	0.004	0.813	47.73	-0.003	-0.721	78.60	-0.001	-0.660	76.48
61	0.005	0.823	49.51	0.003	0.818	29.21	-0.001	-0.706	73.60	-0.002	-0.709	76.17
62	0.002	0.803	41.53	0.004	0.813	50.34	-0.001	-0.755	73.98	-0.002	-0.705	77.93
63	0.006	0.811	50.80	0.002	0.811	36.28	-0.001	-0.747	77.11	-0.001	-0.689	77.50
64	0.002	0.800	31.50	0.006	0.779	49.79	-0.001	-0.732	76.95	-0.002	-0.667	78.28
65	0.003	0.786	35.36	0.006	0.816	45.24	-0.000	-0.662	77.15	-0.002	-0.716	77.38
66	0.004	0.809	46.21	0.005	0.796	41.29	-0.003	-0.737	75.50	-0.001	-0.736	75.42
67	0.002	0.820	51.54	0.006	0.821	45.05	-0.002	-0.668	75.22	-0.002	-0.693	76.51
68	0.002	0.829	39.36	0.005	0.798	50.41	-0.003	-0.698	74.75	-0.003	-0.665	78.60
69	0.006	0.780	42.11	0.003	0.806	35.49	-0.000	-0.674	75.28	-0.003	-0.714	75.22
70	0.003	0.799	42.64	0.001	0.811	39.12	-0.002	-0.696	76.02	-0.002	-0.692	77.16
71	0.006	0.822	29.63	0.003	0.826	39.54	-0.002	-0.721	75.13	-0.003	-0.683	78.35
72	0.001	0.780	46.43	0.005	0.797	36.10	-0.002	-0.691	77.91	-0.001	-0.697	77.43
73	0.003	0.806	39.39	0.006	0.806	36.93	-0.001	-0.703	74.47	-0.002	-0.713	74.38
74	0.003	0.794	44.21	0.004	0.782	30.16	-0.002	-0.658	75.66	-0.002	-0.746	75.85
75	0.004	0.825	46.85	0.001	0.788	49.05	-0.002	-0.748	78.18	-0.001	-0.695	78.58
76	0.007	0.817	29.48	0.006	0.797	31.08	-0.001	-0.737	77.08	-0.002	-0.758	74.89
77	0.005	0.787	49.63	0.004	0.785	44.77	-0.003	-0.692	73.81	-0.001	-0.749	75.94

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T150724-011

Part No : SST3585S

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 150℃, 1000Hrs

Test Date: 2015.06.01 ~ 2015.07.14

Test Standard : JESD22 STANDARD Method-A103

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
1	0.005	0.809	31.38	0.007	0.795	41.01	-0.002	-0.754	76.53	-0.001	-0.702	74.41
2	0.004	0.793	47.85	0.002	0.814	39.95	-0.001	-0.761	75.29	-0.000	-0.736	75.31
3	0.001	0.795	51.69	0.007	0.807	32.63	-0.002	-0.706	73.77	-0.001	-0.686	74.03
4	0.001	0.812	41.87	0.005	0.783	29.53	-0.002	-0.707	77.40	-0.000	-0.763	76.77
5	0.000	0.813	46.02	0.005	0.783	28.95	-0.000	-0.724	77.41	-0.003	-0.704	75.70
6	0.000	0.829	41.70	0.005	0.826	38.07	-0.000	-0.677	76.02	-0.002	-0.707	75.56
7	0.004	0.821	38.63	0.005	0.788	51.35	-0.002	-0.718	77.54	-0.002	-0.716	74.67
8	0.006	0.817	30.56	0.006	0.811	45.40	-0.001	-0.677	77.69	-0.001	-0.708	75.55
9	0.001	0.786	32.43	0.000	0.814	32.31	-0.003	-0.711	74.31	-0.001	-0.760	76.75
10	0.003	0.804	36.22	0.002	0.819	43.95	-0.001	-0.662	76.67	-0.001	-0.755	74.24
11	0.000	0.808	42.08	0.001	0.801	47.46	-0.002	-0.658	78.27	-0.001	-0.665	77.28
12	0.005	0.804	40.81	0.000	0.830	33.00	-0.001	-0.732	77.34	-0.002	-0.750	78.13
13	0.007	0.805	47.21	0.003	0.820	28.97	-0.001	-0.716	73.70	-0.002	-0.743	77.21
14	0.002	0.827	39.89	0.000	0.779	45.93	-0.001	-0.719	76.25	-0.002	-0.701	74.39
15	0.004	0.811	51.41	0.001	0.827	30.73	-0.001	-0.749	75.24	-0.001	-0.708	75.82
16	0.000	0.784	51.31	0.002	0.782	49.35	-0.002	-0.670	77.31	-0.001	-0.743	76.25
17	0.006	0.812	45.50	0.003	0.802	44.78	-0.002	-0.697	74.50	-0.003	-0.668	75.77
18	0.003	0.803	41.42	0.005	0.789	37.02	-0.002	-0.680	76.12	-0.001	-0.703	74.88
19	0.007	0.781	47.40	0.002	0.799	28.90	-0.001	-0.682	75.32	-0.000	-0.733	75.87
20	0.005	0.820	30.57	0.006	0.779	36.15	-0.002	-0.680	77.16	-0.003	-0.737	74.10
21	0.007	0.804	35.69	0.001	0.784	37.78	-0.003	-0.746	74.38	-0.001	-0.683	75.20
22	0.006	0.794	43.49	0.007	0.781	46.59	-0.001	-0.760	74.18	-0.001	-0.759	75.11
23	0.007	0.792	43.71	0.007	0.795	35.53	-0.002	-0.720	78.20	-0.002	-0.666	74.42
24	0.003	0.816	32.84	0.003	0.830	49.12	-0.002	-0.731	77.65	-0.002	-0.697	77.26
25	0.006	0.797	38.26	0.005	0.779	39.06	-0.002	-0.706	75.56	-0.001	-0.701	74.97
26	0.005	0.810	38.36	0.001	0.815	49.52	-0.001	-0.729	75.03	-0.001	-0.703	78.70
27	0.004	0.830	48.35	0.001	0.790	47.94	-0.001	-0.732	78.50	-0.003	-0.666	73.96

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T150724-011

Part No : SST3585S

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 150℃, 1000Hrs

Test Date: 2015.06.01 ~ 2015.07.14

Test Standard : JESD22 STANDARD Method-A103

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
28	0.005	0.803	43.61	0.001	0.779	48.11	-0.002	-0.722	76.36	-0.003	-0.686	77.79
29	0.004	0.802	37.28	0.003	0.811	44.69	-0.001	-0.686	74.34	-0.002	-0.662	78.70
30	0.005	0.798	45.54	0.003	0.808	48.87	-0.001	-0.711	77.09	-0.003	-0.722	77.40
31	0.005	0.825	47.75	0.007	0.814	44.46	-0.002	-0.736	74.94	-0.000	-0.665	78.49
32	0.006	0.817	43.77	0.007	0.794	29.79	-0.002	-0.671	73.70	-0.001	-0.668	78.15
33	0.007	0.821	34.91	0.004	0.804	50.31	-0.002	-0.703	77.93	-0.001	-0.718	74.43
34	0.001	0.796	44.60	0.005	0.787	43.93	-0.002	-0.751	77.51	-0.003	-0.682	75.88
35	0.003	0.806	51.23	0.005	0.796	39.47	-0.000	-0.734	77.57	-0.001	-0.687	78.21
36	0.005	0.787	48.67	0.003	0.813	33.91	-0.001	-0.699	77.53	-0.000	-0.763	75.81
37	0.004	0.789	42.58	0.000	0.787	29.65	-0.002	-0.719	74.40	-0.002	-0.713	76.97
38	0.004	0.794	48.89	0.004	0.805	51.92	-0.001	-0.669	78.55	-0.003	-0.705	75.66
39	0.003	0.799	46.25	0.005	0.827	38.03	-0.000	-0.724	75.37	-0.002	-0.680	74.47
40	0.002	0.783	44.52	0.006	0.799	50.91	-0.002	-0.735	78.69	-0.001	-0.759	75.25
41	0.004	0.791	41.24	0.006	0.827	48.73	-0.003	-0.683	76.62	-0.002	-0.726	76.43
42	0.005	0.802	44.81	0.005	0.827	42.65	-0.001	-0.714	74.03	-0.001	-0.713	75.20
43	0.003	0.814	45.55	0.005	0.811	29.26	-0.002	-0.714	74.25	-0.003	-0.702	74.73
44	0.003	0.807	40.04	0.000	0.799	42.16	-0.001	-0.711	74.81	-0.001	-0.721	76.25
45	0.002	0.794	49.42	0.002	0.794	32.33	-0.003	-0.694	74.97	-0.002	-0.716	77.56
46	0.004	0.785	40.11	0.005	0.786	42.20	-0.001	-0.719	74.90	-0.002	-0.702	78.11
47	0.002	0.813	48.14	0.003	0.783	49.59	-0.002	-0.736	78.04	-0.002	-0.761	75.48
48	0.001	0.790	29.21	0.001	0.803	50.28	-0.000	-0.708	76.51	-0.002	-0.730	75.46
49	0.006	0.813	50.28	0.000	0.804	36.20	-0.002	-0.741	76.65	-0.003	-0.671	77.93
50	0.006	0.781	51.55	0.002	0.791	43.82	-0.002	-0.686	78.42	-0.000	-0.732	77.68
51	0.001	0.803	46.85	0.006	0.789	41.47	-0.000	-0.670	75.04	-0.001	-0.755	77.10
52	0.003	0.787	46.58	0.007	0.787	31.87	-0.002	-0.687	77.53	-0.001	-0.700	76.08
53	0.004	0.815	44.98	0.003	0.781	34.03	-0.001	-0.764	78.57	-0.002	-0.676	74.20
54	0.003	0.797	40.98	0.006	0.828	39.98	-0.001	-0.740	77.76	-0.000	-0.731	75.20

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T150724-011

Part No : SST3585S

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 150℃, 1000Hrs

Test Date: 2015.06.01 ~ 2015.07.14

Test Standard : JESD22 STANDARD Method-A103

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
55	0.002	0.824	41.40	0.002	0.825	48.14	-0.001	-0.661	77.40	-0.002	-0.686	76.29
56	0.002	0.808	38.14	0.007	0.792	34.73	-0.000	-0.699	78.16	-0.002	-0.664	76.01
57	0.002	0.782	40.77	0.004	0.825	41.01	-0.002	-0.761	75.77	-0.003	-0.762	74.27
58	0.000	0.826	38.47	0.005	0.818	34.76	-0.000	-0.752	73.70	-0.002	-0.693	77.75
59	0.006	0.806	29.97	0.006	0.814	43.12	-0.000	-0.692	75.18	-0.002	-0.711	77.00
60	0.002	0.794	49.03	0.007	0.782	40.95	-0.003	-0.695	78.63	-0.001	-0.760	76.16
61	0.005	0.828	48.72	0.004	0.818	46.46	-0.001	-0.746	76.66	-0.002	-0.738	75.72
62	0.001	0.819	36.65	0.001	0.809	48.53	-0.001	-0.701	78.00	-0.002	-0.712	77.07
63	0.003	0.819	37.50	0.002	0.789	29.80	-0.001	-0.725	76.84	-0.001	-0.678	73.97
64	0.006	0.790	50.41	0.004	0.827	29.30	-0.001	-0.754	75.64	-0.001	-0.710	75.28
65	0.004	0.799	32.12	0.007	0.803	46.81	-0.000	-0.666	76.44	-0.003	-0.734	75.70
66	0.006	0.780	41.95	0.004	0.819	38.32	-0.000	-0.685	76.69	-0.001	-0.676	74.24
67	0.006	0.804	40.71	0.002	0.802	38.36	-0.001	-0.692	78.54	-0.002	-0.725	78.05
68	0.001	0.792	42.97	0.003	0.817	38.61	-0.000	-0.716	78.17	-0.002	-0.739	74.41
69	0.004	0.818	35.25	0.005	0.779	44.43	-0.001	-0.699	78.62	-0.002	-0.708	74.37
70	0.001	0.812	30.93	0.001	0.818	37.35	-0.001	-0.683	74.36	-0.001	-0.743	77.36
71	0.003	0.827	31.33	0.007	0.804	37.21	-0.000	-0.693	74.95	-0.001	-0.739	76.52
72	0.003	0.830	50.59	0.001	0.789	44.30	-0.003	-0.732	74.79	-0.002	-0.664	75.43
73	0.004	0.795	47.89	0.000	0.797	41.33	-0.002	-0.745	78.71	-0.002	-0.712	75.87
74	0.002	0.802	37.22	0.005	0.813	36.93	-0.002	-0.684	73.84	-0.002	-0.733	76.72
75	0.001	0.816	37.07	0.004	0.822	36.08	-0.003	-0.689	76.87	-0.000	-0.688	73.61
76	0.001	0.799	34.18	0.003	0.820	35.32	-0.000	-0.659	77.89	-0.000	-0.749	78.23
77	0.001	0.822	46.59	0.003	0.800	47.52	-0.002	-0.741	78.40	-0.002	-0.745	75.36

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Pressure Cooker Test Data

Report No : T150724-011

Part No : SST3585S

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2015.06.02 ~ 2015.06.10

Test Standard : JESD22 STANDARD Method-A102

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
1	0.004	0.827	38.16	0.001	0.824	44.05	-0.001	-0.672	75.71	-0.003	-0.761	75.28
2	0.007	0.789	40.28	0.005	0.808	40.43	-0.003	-0.751	77.40	-0.001	-0.748	73.55
3	0.006	0.827	31.32	0.006	0.809	42.07	-0.001	-0.748	74.77	-0.002	-0.709	73.56
4	0.004	0.819	38.94	0.007	0.791	30.93	-0.003	-0.682	77.03	-0.003	-0.758	75.54
5	0.006	0.789	39.99	0.006	0.808	39.99	-0.001	-0.755	75.54	-0.003	-0.675	75.24
6	0.003	0.813	47.12	0.000	0.790	34.67	-0.001	-0.743	74.45	-0.001	-0.659	77.20
7	0.003	0.786	50.36	0.005	0.798	28.76	-0.002	-0.743	73.56	-0.001	-0.666	74.54
8	0.007	0.800	51.13	0.003	0.802	32.22	-0.003	-0.728	78.27	-0.001	-0.659	77.21
9	0.000	0.814	42.87	0.001	0.795	37.25	-0.001	-0.661	76.81	-0.001	-0.754	78.22
10	0.004	0.822	50.83	0.003	0.831	43.59	-0.002	-0.761	78.30	-0.003	-0.697	74.56
11	0.004	0.829	34.09	0.001	0.825	38.26	-0.002	-0.737	75.69	-0.000	-0.747	74.04
12	0.005	0.796	47.96	0.007	0.793	35.31	-0.001	-0.729	76.58	-0.002	-0.715	76.87
13	0.004	0.826	37.74	0.004	0.803	35.73	-0.001	-0.678	74.37	-0.002	-0.716	76.97
14	0.004	0.800	47.46	0.007	0.807	51.11	-0.000	-0.711	78.06	-0.002	-0.731	74.35
15	0.007	0.790	51.30	0.005	0.813	34.06	-0.002	-0.685	75.64	-0.001	-0.705	76.60
16	0.005	0.808	51.80	0.006	0.827	51.39	-0.003	-0.756	76.44	-0.001	-0.659	77.44
17	0.006	0.796	38.54	0.005	0.803	37.27	-0.001	-0.682	78.25	-0.001	-0.686	73.75
18	0.004	0.785	39.95	0.005	0.791	28.93	-0.003	-0.696	77.36	-0.003	-0.745	76.56
19	0.002	0.807	43.38	0.007	0.801	38.48	-0.000	-0.701	74.04	-0.001	-0.667	74.30
20	0.005	0.825	38.76	0.005	0.818	42.32	-0.000	-0.760	76.57	-0.001	-0.683	74.89
21	0.002	0.827	51.36	0.000	0.797	31.08	-0.002	-0.687	78.41	-0.000	-0.709	76.26
22	0.003	0.827	46.56	0.002	0.796	36.20	-0.001	-0.739	78.69	-0.001	-0.759	78.07
23	0.003	0.795	45.15	0.004	0.799	32.85	-0.001	-0.753	75.44	-0.001	-0.754	76.53
24	0.006	0.818	48.87	0.006	0.829	45.56	-0.001	-0.694	75.87	-0.002	-0.700	78.21
25	0.003	0.828	51.69	0.000	0.825	50.97	-0.002	-0.707	74.48	-0.000	-0.719	75.09
26	0.000	0.780	45.26	0.001	0.790	33.62	-0.002	-0.734	75.97	-0.002	-0.685	75.98
27	0.003	0.822	28.64	0.002	0.817	36.44	-0.001	-0.754	75.54	-0.002	-0.720	76.07

SeCoS Corporation

Pressure Cooker Test Data

Report No : T150724-011

Part No : SST3585S

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2015.06.02 ~ 2015.06.10

Test Standard : JESD22 STANDARD Method-A102

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
28	0.001	0.795	30.44	0.002	0.793	36.96	-0.003	-0.680	75.03	-0.002	-0.720	77.95
29	0.002	0.795	49.40	0.001	0.804	35.07	-0.001	-0.714	78.55	-0.000	-0.677	77.19
30	0.002	0.800	39.91	0.003	0.819	46.34	-0.003	-0.747	74.83	-0.001	-0.703	77.85
31	0.005	0.823	50.63	0.002	0.830	38.02	-0.002	-0.701	74.06	-0.001	-0.715	76.36
32	0.001	0.809	51.70	0.003	0.795	45.40	-0.000	-0.705	74.11	-0.001	-0.696	77.64
33	0.003	0.824	50.88	0.002	0.823	44.48	-0.002	-0.698	76.56	-0.002	-0.694	73.70
34	0.005	0.808	50.83	0.004	0.817	30.31	-0.001	-0.751	73.76	-0.001	-0.712	78.05
35	0.006	0.798	50.88	0.002	0.828	44.23	-0.003	-0.744	74.14	-0.002	-0.699	74.13
36	0.001	0.781	45.63	0.007	0.829	37.49	-0.003	-0.691	77.31	-0.002	-0.704	74.53
37	0.004	0.812	32.99	0.005	0.831	44.81	-0.002	-0.677	75.97	-0.001	-0.719	74.65
38	0.002	0.781	37.45	0.004	0.785	32.69	-0.001	-0.760	77.53	-0.001	-0.700	75.52
39	0.001	0.813	41.77	0.001	0.794	38.33	-0.000	-0.666	78.42	-0.003	-0.686	77.54
40	0.004	0.808	49.26	0.003	0.796	28.88	-0.000	-0.735	76.20	-0.002	-0.756	74.47
41	0.000	0.797	35.75	0.000	0.808	43.21	-0.002	-0.748	75.06	-0.002	-0.697	77.40
42	0.002	0.819	49.33	0.005	0.802	33.54	-0.000	-0.706	75.43	-0.001	-0.759	78.58
43	0.005	0.825	36.65	0.004	0.828	31.14	-0.003	-0.756	74.70	-0.002	-0.711	76.29
44	0.002	0.809	50.21	0.003	0.787	30.81	-0.001	-0.760	77.64	-0.000	-0.734	74.46
45	0.003	0.796	36.80	0.005	0.796	38.21	-0.001	-0.705	78.28	-0.001	-0.660	77.78
46	0.002	0.824	43.39	0.004	0.829	48.41	-0.003	-0.711	76.76	-0.002	-0.735	76.43
47	0.002	0.792	33.07	0.005	0.788	36.38	-0.002	-0.664	78.69	-0.003	-0.715	74.83
48	0.002	0.814	36.36	0.002	0.793	40.90	-0.000	-0.696	73.72	-0.003	-0.710	76.13
49	0.007	0.819	29.40	0.006	0.798	44.90	-0.001	-0.660	77.28	-0.001	-0.727	75.74
50	0.005	0.811	47.73	0.000	0.791	36.06	-0.001	-0.660	76.85	-0.001	-0.758	77.77
51	0.005	0.797	38.82	0.001	0.803	39.98	-0.002	-0.742	77.91	-0.003	-0.668	78.09
52	0.004	0.828	44.34	0.001	0.798	33.77	-0.003	-0.744	74.13	-0.003	-0.673	75.47
53	0.003	0.788	45.18	0.003	0.810	46.03	-0.001	-0.722	76.80	-0.002	-0.706	78.36
54	0.007	0.800	43.82	0.005	0.817	48.94	-0.000	-0.753	77.39	-0.002	-0.735	78.02

SeCoS Corporation

Pressure Cooker Test Data

Report No : T150724-011

Part No : SST3585S

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)

P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2015.06.02 ~ 2015.06.10

Test Standard : JESD22 STANDARD Method-A102

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
55	0.007	0.819	31.39	0.002	0.815	46.01	-0.001	-0.687	76.82	-0.003	-0.751	78.71
56	0.006	0.795	43.60	0.002	0.806	42.32	-0.001	-0.665	76.02	-0.002	-0.707	74.50
57	0.005	0.791	29.64	0.002	0.822	36.69	-0.000	-0.730	78.58	-0.001	-0.749	77.88
58	0.005	0.799	47.26	0.005	0.830	46.85	-0.002	-0.676	78.19	-0.002	-0.748	77.59
59	0.001	0.817	34.58	0.004	0.792	39.46	-0.001	-0.662	76.78	-0.003	-0.744	78.13
60	0.005	0.821	46.97	0.003	0.826	44.28	-0.002	-0.736	77.22	-0.003	-0.695	76.31
61	0.006	0.815	33.39	0.002	0.809	38.93	-0.002	-0.749	74.47	-0.002	-0.699	78.52
62	0.001	0.818	39.70	0.003	0.801	48.63	-0.001	-0.669	75.11	-0.000	-0.669	77.96
63	0.006	0.790	44.45	0.001	0.821	38.46	-0.002	-0.665	76.32	-0.002	-0.762	76.78
64	0.002	0.800	31.47	0.007	0.811	40.73	-0.003	-0.671	73.80	-0.003	-0.661	73.83
65	0.005	0.802	29.57	0.006	0.779	34.73	-0.001	-0.694	75.90	-0.001	-0.726	78.65
66	0.005	0.829	34.88	0.003	0.827	35.05	-0.001	-0.668	78.32	-0.001	-0.744	77.79
67	0.007	0.803	36.70	0.004	0.784	42.30	-0.000	-0.671	74.28	-0.002	-0.685	75.91
68	0.001	0.785	49.55	0.007	0.818	40.91	-0.002	-0.732	76.19	-0.000	-0.669	74.71
69	0.000	0.787	34.49	0.006	0.797	40.61	-0.001	-0.698	75.29	-0.000	-0.714	75.16
70	0.005	0.795	29.52	0.005	0.804	38.46	-0.002	-0.713	75.93	-0.002	-0.757	74.07
71	0.004	0.818	36.36	0.005	0.804	30.43	-0.001	-0.713	74.50	-0.001	-0.693	76.96
72	0.002	0.814	36.73	0.001	0.807	28.73	-0.002	-0.724	76.36	-0.002	-0.750	76.33
73	0.002	0.800	37.39	0.005	0.823	43.22	-0.001	-0.726	74.57	-0.002	-0.726	78.60
74	0.003	0.804	43.86	0.001	0.803	40.64	-0.002	-0.723	78.55	-0.002	-0.703	75.04
75	0.001	0.796	30.02	0.006	0.780	41.90	-0.001	-0.691	75.09	-0.002	-0.750	74.34
76	0.006	0.781	38.93	0.003	0.809	29.90	-0.001	-0.713	78.06	-0.001	-0.690	76.08
77	0.000	0.809	32.96	0.001	0.830	51.38	-0.001	-0.729	76.65	-0.003	-0.671	77.79

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Temperature Cycle Test Data

Report No : T150724-011

Part No : SST3585S

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle

Test Date: 2015.06.02 ~ 2015.07.24

Test Standard : JESD22 STANDARD Method-A104

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
1	0.002	0.796	42.32	0.003	0.829	51.73	-0.002	-0.760	75.70	-0.002	-0.749	76.58
2	0.001	0.819	47.06	0.005	0.804	41.67	-0.000	-0.684	76.49	-0.002	-0.724	73.56
3	0.006	0.797	33.03	0.004	0.801	41.67	-0.000	-0.756	78.66	-0.002	-0.675	76.73
4	0.004	0.829	37.56	0.005	0.808	40.83	-0.003	-0.732	77.54	-0.002	-0.712	76.82
5	0.007	0.784	36.83	0.006	0.818	37.34	-0.001	-0.681	74.71	-0.002	-0.740	76.76
6	0.001	0.789	34.95	0.001	0.805	50.31	-0.000	-0.704	77.44	-0.002	-0.699	75.27
7	0.001	0.818	32.76	0.004	0.828	51.26	-0.003	-0.708	76.79	-0.002	-0.682	77.15
8	0.006	0.807	42.75	0.003	0.828	28.55	-0.002	-0.740	74.73	-0.002	-0.743	73.73
9	0.000	0.829	48.56	0.003	0.800	46.00	-0.002	-0.727	73.98	-0.002	-0.689	77.12
10	0.002	0.778	35.80	0.001	0.810	31.17	-0.002	-0.681	78.28	-0.002	-0.673	75.03
11	0.006	0.825	35.07	0.003	0.788	44.07	-0.001	-0.666	75.44	-0.002	-0.699	75.73
12	0.001	0.822	39.49	0.002	0.792	41.48	-0.001	-0.669	75.69	-0.002	-0.667	78.51
13	0.006	0.797	34.65	0.003	0.783	44.88	-0.001	-0.738	73.67	-0.000	-0.734	78.42
14	0.004	0.809	29.10	0.005	0.826	40.54	-0.002	-0.706	78.45	-0.002	-0.756	77.23
15	0.002	0.806	45.18	0.007	0.784	50.11	-0.001	-0.755	77.91	-0.001	-0.719	76.48
16	0.003	0.797	51.03	0.006	0.791	37.51	-0.003	-0.666	75.87	-0.001	-0.695	78.00
17	0.005	0.821	29.67	0.007	0.821	36.63	-0.001	-0.742	78.30	-0.003	-0.680	78.24
18	0.005	0.824	50.47	0.006	0.786	42.32	-0.000	-0.709	74.28	-0.002	-0.662	76.43
19	0.002	0.809	36.66	0.000	0.795	39.25	-0.002	-0.674	74.95	-0.001	-0.671	78.00
20	0.005	0.803	46.01	0.002	0.783	34.03	-0.000	-0.709	78.58	-0.000	-0.661	77.79
21	0.006	0.831	32.36	0.007	0.806	46.58	-0.001	-0.688	75.23	-0.000	-0.715	78.68
22	0.003	0.812	45.53	0.005	0.805	37.21	-0.001	-0.663	74.25	-0.003	-0.692	76.66
23	0.005	0.829	44.57	0.003	0.800	46.44	-0.002	-0.696	73.68	-0.002	-0.683	75.10
24	0.002	0.799	51.66	0.002	0.781	35.59	-0.001	-0.692	78.20	-0.002	-0.742	77.20
25	0.000	0.809	42.53	0.005	0.793	36.93	-0.002	-0.681	76.19	-0.002	-0.726	74.14
26	0.003	0.797	30.86	0.005	0.812	48.31	-0.001	-0.696	74.39	-0.002	-0.739	74.83
27	0.002	0.811	31.56	0.003	0.824	44.73	-0.003	-0.741	76.90	-0.001	-0.685	78.00

SeCoS Corporation

Temperature Cycle Test Data

Report No : T150724-011

Part No : SST3585S

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle

Test Date: 2015.06.02 ~ 2015.07.24

Test Standard : JESD22 STANDARD Method-A104

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
28	0.003	0.797	31.92	0.004	0.783	38.40	-0.001	-0.688	76.12	-0.003	-0.672	76.46
29	0.006	0.780	39.90	0.004	0.780	38.04	-0.003	-0.737	77.46	-0.003	-0.672	77.29
30	0.002	0.816	36.16	0.001	0.813	41.31	-0.002	-0.729	77.87	-0.002	-0.762	73.61
31	0.001	0.811	32.18	0.006	0.804	40.57	-0.002	-0.685	76.18	-0.000	-0.678	75.94
32	0.002	0.804	46.48	0.004	0.802	38.33	-0.002	-0.758	74.41	-0.003	-0.721	76.08
33	0.007	0.814	39.74	0.004	0.802	36.04	-0.000	-0.708	77.64	-0.000	-0.676	77.49
34	0.007	0.794	34.71	0.004	0.811	47.87	-0.001	-0.704	78.69	-0.003	-0.663	78.49
35	0.003	0.798	43.75	0.001	0.826	46.61	-0.002	-0.724	76.50	-0.002	-0.755	77.96
36	0.000	0.827	39.45	0.002	0.799	30.26	-0.000	-0.752	74.12	-0.002	-0.725	73.71
37	0.002	0.795	34.76	0.006	0.791	49.51	-0.001	-0.679	74.08	-0.002	-0.679	77.83
38	0.007	0.809	42.24	0.006	0.796	36.15	-0.000	-0.745	73.90	-0.002	-0.680	77.68
39	0.003	0.781	45.78	0.000	0.828	46.00	-0.001	-0.697	74.00	-0.001	-0.688	77.21
40	0.005	0.786	33.74	0.001	0.817	39.40	-0.001	-0.671	74.00	-0.000	-0.711	74.62
41	0.005	0.786	29.03	0.005	0.792	34.90	-0.003	-0.743	75.01	-0.002	-0.723	78.48
42	0.004	0.828	38.89	0.001	0.828	48.38	-0.001	-0.679	75.51	-0.002	-0.685	74.64
43	0.006	0.779	44.69	0.006	0.823	30.00	-0.001	-0.709	78.14	-0.002	-0.752	76.12
44	0.001	0.810	34.50	0.001	0.782	50.54	-0.002	-0.719	75.69	-0.003	-0.741	75.02
45	0.001	0.823	36.92	0.005	0.791	34.12	-0.000	-0.701	74.09	-0.001	-0.721	76.24
46	0.003	0.816	45.35	0.004	0.807	50.19	-0.001	-0.754	76.33	-0.002	-0.688	75.30
47	0.003	0.808	30.73	0.006	0.792	44.67	-0.002	-0.675	77.89	-0.003	-0.673	78.71
48	0.000	0.784	41.67	0.001	0.785	50.46	-0.003	-0.739	76.60	-0.001	-0.742	78.20
49	0.001	0.790	29.29	0.003	0.817	51.38	-0.000	-0.684	74.02	-0.003	-0.701	77.19
50	0.001	0.790	47.74	0.002	0.825	48.56	-0.001	-0.666	75.37	-0.002	-0.761	75.14
51	0.003	0.795	31.48	0.005	0.804	34.16	-0.003	-0.664	74.38	-0.000	-0.666	73.90
52	0.007	0.800	43.66	0.002	0.809	48.67	-0.001	-0.739	74.77	-0.001	-0.661	73.66
53	0.007	0.826	50.23	0.003	0.801	29.38	-0.002	-0.663	73.75	-0.000	-0.673	74.35
54	0.002	0.804	38.25	0.004	0.808	50.15	-0.002	-0.739	77.69	-0.000	-0.748	78.64

SeCoS Corporation

Temperature Cycle Test Data

Report No : T150724-011

Part No : SST3585S

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle

Test Date: 2015.06.02 ~ 2015.07.24

Test Standard : JESD22 STANDARD Method-A104

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
55	0.002	0.793	30.83	0.001	0.819	44.18	-0.002	-0.737	74.08	-0.001	-0.764	74.12
56	0.004	0.815	30.48	0.007	0.802	38.09	-0.002	-0.755	78.54	-0.001	-0.757	75.23
57	0.004	0.798	28.69	0.006	0.792	35.48	-0.001	-0.722	74.23	-0.002	-0.696	74.16
58	0.005	0.795	45.20	0.004	0.823	39.22	-0.001	-0.658	78.11	-0.002	-0.674	74.67
59	0.004	0.792	39.49	0.006	0.797	35.42	-0.001	-0.751	74.41	-0.001	-0.705	74.48
60	0.007	0.822	35.91	0.007	0.827	50.74	-0.000	-0.699	78.29	-0.001	-0.725	74.48
61	0.003	0.811	30.49	0.006	0.797	35.61	-0.000	-0.748	75.94	-0.002	-0.747	78.17
62	0.001	0.823	29.55	0.006	0.818	33.57	-0.003	-0.748	78.01	-0.001	-0.760	77.95
63	0.005	0.784	34.78	0.003	0.828	36.10	-0.002	-0.677	76.54	-0.000	-0.704	73.70
64	0.003	0.816	31.68	0.006	0.780	34.64	-0.002	-0.736	74.87	-0.003	-0.744	77.80
65	0.003	0.792	47.06	0.006	0.794	43.16	-0.003	-0.754	74.80	-0.001	-0.687	77.84
66	0.000	0.826	49.51	0.005	0.828	34.53	-0.001	-0.724	77.54	-0.001	-0.702	77.26
67	0.006	0.821	34.58	0.003	0.797	37.60	-0.003	-0.693	77.33	-0.002	-0.750	75.82
68	0.002	0.806	40.35	0.006	0.819	46.76	-0.001	-0.764	74.10	-0.001	-0.694	74.35
69	0.006	0.828	38.21	0.006	0.805	43.75	-0.002	-0.697	77.35	-0.002	-0.759	77.31
70	0.006	0.810	34.66	0.003	0.806	30.63	-0.001	-0.748	74.07	-0.001	-0.677	78.64
71	0.002	0.787	35.12	0.004	0.784	46.50	-0.001	-0.750	74.51	-0.000	-0.718	75.51
72	0.002	0.825	51.12	0.006	0.810	39.50	-0.000	-0.704	77.31	-0.002	-0.747	76.99
73	0.005	0.815	38.12	0.005	0.812	35.75	-0.002	-0.704	74.76	-0.002	-0.665	74.53
74	0.006	0.786	42.19	0.005	0.812	42.05	-0.000	-0.744	77.63	-0.003	-0.754	76.80
75	0.003	0.826	45.35	0.003	0.815	47.74	-0.002	-0.742	74.05	-0.002	-0.753	76.84
76	0.003	0.828	46.16	0.002	0.802	50.05	-0.001	-0.757	78.05	-0.003	-0.694	77.53
77	0.007	0.780	32.96	0.003	0.784	28.58	-0.001	-0.719	77.97	-0.002	-0.695	76.97

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T150724-011

Part No : SST3585S

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 85±2℃, 85±5%RH, 1000Hrs

Test Date: 2015.06.11 ~ 2015.07.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
1	0.007	0.828	35.85	0.000	0.779	41.97	-0.001	-0.676	77.79	-0.002	-0.717	74.30
2	0.002	0.807	37.20	0.001	0.812	38.75	-0.002	-0.684	75.52	-0.003	-0.754	76.24
3	0.003	0.807	29.42	0.006	0.825	39.00	-0.002	-0.763	74.74	-0.000	-0.740	73.87
4	0.006	0.792	33.75	0.001	0.800	30.59	-0.002	-0.754	77.62	-0.001	-0.742	76.26
5	0.004	0.805	31.72	0.003	0.809	36.29	-0.002	-0.729	75.65	-0.003	-0.675	77.84
6	0.002	0.804	30.65	0.005	0.784	44.34	-0.001	-0.708	76.23	-0.001	-0.744	78.19
7	0.000	0.815	38.50	0.006	0.829	33.30	-0.003	-0.702	76.07	-0.003	-0.763	78.51
8	0.003	0.791	35.05	0.003	0.827	48.55	-0.001	-0.683	77.30	-0.001	-0.740	74.39
9	0.001	0.817	31.51	0.005	0.802	41.71	-0.001	-0.758	75.06	-0.000	-0.702	76.81
10	0.004	0.815	31.06	0.003	0.808	33.37	-0.001	-0.690	73.91	-0.001	-0.758	74.65
11	0.007	0.803	42.50	0.001	0.803	49.57	-0.002	-0.699	78.48	-0.001	-0.764	73.65
12	0.001	0.829	38.48	0.001	0.792	50.77	-0.002	-0.672	78.12	-0.003	-0.701	74.33
13	0.001	0.818	49.43	0.003	0.799	36.69	-0.000	-0.746	74.28	-0.002	-0.739	77.55
14	0.001	0.822	50.76	0.002	0.816	44.78	-0.001	-0.719	76.71	-0.000	-0.670	76.18
15	0.006	0.829	29.32	0.003	0.782	49.82	-0.001	-0.761	76.49	-0.002	-0.667	76.41
16	0.002	0.822	35.34	0.005	0.822	51.80	-0.002	-0.696	76.57	-0.003	-0.687	73.92
17	0.004	0.814	35.40	0.000	0.827	28.69	-0.002	-0.681	77.44	-0.000	-0.763	74.21
18	0.006	0.823	48.04	0.002	0.789	40.82	-0.000	-0.705	73.53	-0.001	-0.669	75.55
19	0.005	0.781	36.42	0.005	0.785	45.28	-0.002	-0.676	74.10	-0.001	-0.745	75.82
20	0.000	0.822	50.49	0.003	0.781	44.48	-0.003	-0.719	77.42	-0.003	-0.711	77.98
21	0.006	0.813	34.57	0.007	0.786	31.56	-0.002	-0.666	77.88	-0.000	-0.722	77.06
22	0.000	0.809	48.15	0.001	0.781	39.72	-0.002	-0.755	74.86	-0.002	-0.713	75.58
23	0.004	0.817	36.05	0.006	0.782	47.79	-0.000	-0.749	78.62	-0.001	-0.660	77.37
24	0.002	0.801	39.65	0.006	0.803	42.32	-0.003	-0.734	78.42	-0.003	-0.689	75.26
25	0.005	0.803	35.66	0.005	0.823	37.76	-0.001	-0.761	74.36	-0.003	-0.740	75.48
26	0.004	0.806	39.52	0.001	0.783	48.22	-0.001	-0.681	77.09	-0.002	-0.730	74.35
27	0.000	0.806	44.83	0.003	0.821	49.57	-0.002	-0.690	77.24	-0.003	-0.710	78.47

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T150724-011

Part No : SST3585S

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 85±2℃, 85±5%RH, 1000Hrs

Test Date: 2015.06.11 ~ 2015.07.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
28	0.006	0.809	35.76	0.001	0.789	45.28	-0.001	-0.689	76.96	-0.001	-0.703	73.65
29	0.004	0.803	49.14	0.002	0.814	32.05	-0.003	-0.709	73.74	-0.002	-0.698	76.63
30	0.005	0.817	33.92	0.002	0.805	48.27	-0.001	-0.716	75.85	-0.002	-0.749	77.11
31	0.002	0.794	32.70	0.005	0.778	42.22	-0.002	-0.704	73.72	-0.001	-0.687	74.17
32	0.006	0.798	46.02	0.001	0.826	46.23	-0.002	-0.733	74.00	-0.002	-0.707	76.91
33	0.003	0.784	30.41	0.001	0.826	39.60	-0.002	-0.660	76.91	-0.001	-0.728	76.51
34	0.002	0.827	46.31	0.007	0.815	51.67	-0.003	-0.720	76.39	-0.000	-0.666	78.63
35	0.005	0.822	41.76	0.002	0.801	38.63	-0.003	-0.688	77.32	-0.002	-0.724	78.34
36	0.000	0.800	39.79	0.004	0.801	44.45	-0.001	-0.705	78.53	-0.002	-0.749	77.31
37	0.002	0.783	46.44	0.006	0.799	36.40	-0.002	-0.754	74.40	-0.001	-0.677	76.61
38	0.006	0.814	28.79	0.002	0.815	36.81	-0.000	-0.680	74.42	-0.002	-0.678	77.55
39	0.005	0.811	28.53	0.003	0.821	40.28	-0.001	-0.748	75.97	-0.002	-0.731	74.07
40	0.007	0.809	50.68	0.000	0.825	50.25	-0.000	-0.686	78.63	-0.001	-0.754	78.32
41	0.007	0.782	49.85	0.006	0.816	36.94	-0.000	-0.714	77.82	-0.002	-0.701	77.31
42	0.006	0.790	49.07	0.004	0.804	32.06	-0.000	-0.728	75.51	-0.000	-0.693	74.84
43	0.001	0.794	30.12	0.005	0.786	32.31	-0.001	-0.671	78.54	-0.002	-0.741	74.79
44	0.006	0.811	30.42	0.000	0.830	40.53	-0.000	-0.753	74.19	-0.003	-0.702	74.46
45	0.001	0.812	43.34	0.002	0.792	38.65	-0.001	-0.730	78.57	-0.001	-0.672	74.72
46	0.004	0.803	38.02	0.000	0.803	50.07	-0.003	-0.726	74.72	-0.001	-0.749	77.99
47	0.002	0.795	33.92	0.006	0.804	29.71	-0.001	-0.732	77.72	-0.001	-0.707	77.11
48	0.002	0.831	44.09	0.001	0.826	31.99	-0.000	-0.658	76.89	-0.002	-0.729	75.41
49	0.001	0.793	35.35	0.005	0.784	30.73	-0.002	-0.755	75.14	-0.002	-0.733	76.27
50	0.004	0.821	35.31	0.001	0.803	39.27	-0.003	-0.700	75.50	-0.000	-0.699	76.30
51	0.002	0.820	32.93	0.006	0.799	49.20	-0.001	-0.697	76.11	-0.003	-0.697	77.91
52	0.001	0.791	31.36	0.004	0.817	35.64	-0.000	-0.720	78.49	-0.002	-0.751	77.56
53	0.000	0.807	32.67	0.001	0.815	41.09	-0.001	-0.694	77.28	-0.003	-0.741	75.93
54	0.000	0.831	48.49	0.003	0.792	35.64	-0.001	-0.700	74.74	-0.003	-0.688	75.67

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T150724-011

Part No : SST3585S

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 85±2℃, 85±5%RH, 1000Hrs

Test Date: 2015.06.11 ~ 2015.07.23

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
55	0.006	0.826	48.63	0.007	0.791	32.62	-0.002	-0.688	76.87	-0.003	-0.698	74.75
56	0.006	0.788	44.86	0.005	0.807	33.50	-0.001	-0.694	75.24	-0.003	-0.738	78.51
57	0.004	0.794	45.36	0.004	0.807	29.31	-0.001	-0.763	76.13	-0.001	-0.686	74.24
58	0.006	0.782	37.41	0.004	0.821	47.97	-0.001	-0.693	74.07	-0.001	-0.667	75.17
59	0.006	0.805	38.90	0.005	0.823	37.47	-0.002	-0.729	78.24	-0.001	-0.703	77.34
60	0.002	0.788	40.64	0.003	0.830	38.52	-0.002	-0.668	76.88	-0.003	-0.677	74.57
61	0.005	0.779	39.47	0.001	0.797	30.13	-0.001	-0.710	73.81	-0.001	-0.746	74.99
62	0.006	0.791	35.65	0.001	0.798	45.72	-0.002	-0.721	76.79	-0.003	-0.665	78.54
63	0.003	0.812	38.39	0.005	0.826	50.93	-0.001	-0.740	74.40	-0.002	-0.747	76.90
64	0.007	0.780	48.56	0.002	0.802	32.12	-0.001	-0.753	73.74	-0.002	-0.757	75.47
65	0.000	0.791	45.05	0.001	0.793	35.82	-0.001	-0.707	74.32	-0.002	-0.751	73.87
66	0.002	0.807	38.08	0.001	0.788	46.11	-0.001	-0.736	73.94	-0.001	-0.726	75.49
67	0.006	0.807	47.17	0.002	0.809	36.02	-0.001	-0.668	75.33	-0.002	-0.707	76.77
68	0.004	0.806	43.67	0.006	0.817	44.60	-0.002	-0.699	78.64	-0.002	-0.725	76.39
69	0.005	0.826	44.07	0.000	0.822	45.39	-0.002	-0.740	75.02	-0.001	-0.718	74.57
70	0.001	0.807	32.86	0.003	0.807	36.21	-0.002	-0.755	76.05	-0.002	-0.704	75.77
71	0.001	0.781	32.28	0.007	0.786	40.33	-0.002	-0.733	78.06	-0.001	-0.744	77.52
72	0.000	0.807	43.24	0.002	0.781	45.87	-0.002	-0.757	78.34	-0.003	-0.739	74.93
73	0.006	0.830	40.04	0.005	0.823	33.90	-0.000	-0.747	75.82	-0.003	-0.761	74.31
74	0.005	0.786	33.77	0.004	0.808	35.97	-0.000	-0.699	74.23	-0.001	-0.707	77.92
75	0.006	0.802	50.96	0.001	0.809	28.99	-0.002	-0.716	77.27	-0.000	-0.702	75.79
76	0.003	0.816	44.46	0.003	0.780	51.76	-0.000	-0.754	77.68	-0.002	-0.756	73.93
77	0.005	0.808	37.30	0.002	0.821	38.90	-0.001	-0.697	74.99	-0.000	-0.702	77.34

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T150724-011

Part No : SST3585S

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs

Test Date: 2015.06.12 ~ 2015.07.24

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
1	0.001	0.791	38.15	0.004	0.811	38.79	-0.003	-0.688	77.89	-0.002	-0.746	74.74
2	0.002	0.798	40.42	0.001	0.781	51.90	-0.003	-0.719	74.30	-0.000	-0.680	75.91
3	0.007	0.779	50.13	0.004	0.826	31.62	-0.002	-0.759	78.02	-0.002	-0.762	75.55
4	0.002	0.785	35.02	0.004	0.797	32.46	-0.002	-0.698	74.03	-0.001	-0.664	78.31
5	0.006	0.812	32.91	0.001	0.791	39.16	-0.002	-0.743	74.72	-0.002	-0.671	74.74
6	0.002	0.822	41.72	0.007	0.827	50.02	-0.002	-0.738	75.77	-0.002	-0.703	77.57
7	0.007	0.800	41.91	0.006	0.810	28.78	-0.000	-0.763	78.30	-0.002	-0.666	74.08
8	0.006	0.791	43.53	0.005	0.827	34.92	-0.000	-0.695	73.65	-0.002	-0.706	76.34
9	0.002	0.810	45.71	0.001	0.795	28.58	-0.002	-0.671	73.94	-0.002	-0.751	74.15
10	0.001	0.800	42.06	0.003	0.825	34.23	-0.002	-0.671	77.61	-0.003	-0.701	78.66
11	0.003	0.818	32.16	0.006	0.796	48.16	-0.003	-0.724	76.29	-0.003	-0.755	76.10
12	0.000	0.825	34.03	0.004	0.821	35.00	-0.002	-0.752	77.74	-0.003	-0.670	75.76
13	0.007	0.797	40.81	0.001	0.824	37.96	-0.003	-0.753	75.74	-0.002	-0.742	78.22
14	0.004	0.781	30.04	0.004	0.822	51.50	-0.001	-0.658	73.58	-0.001	-0.750	78.50
15	0.002	0.825	43.97	0.005	0.790	48.89	-0.002	-0.662	75.09	-0.003	-0.677	77.81
16	0.007	0.824	29.23	0.005	0.813	50.84	-0.002	-0.711	75.95	-0.000	-0.666	78.48
17	0.004	0.788	49.45	0.006	0.784	30.52	-0.001	-0.693	74.70	-0.002	-0.704	76.90
18	0.005	0.824	39.69	0.002	0.823	44.87	-0.000	-0.658	77.14	-0.001	-0.758	76.96
19	0.003	0.800	37.07	0.000	0.815	49.43	-0.002	-0.720	76.31	-0.002	-0.754	74.69
20	0.005	0.797	36.05	0.003	0.801	51.74	-0.003	-0.663	75.63	-0.001	-0.752	74.06
21	0.004	0.808	51.39	0.006	0.806	33.74	-0.001	-0.745	76.64	-0.002	-0.697	76.69
22	0.006	0.795	45.78	0.002	0.818	32.12	-0.000	-0.728	76.75	-0.001	-0.713	76.89
23	0.006	0.801	43.05	0.006	0.794	29.66	-0.000	-0.665	73.88	-0.000	-0.759	74.00
24	0.007	0.808	47.38	0.002	0.781	48.09	-0.002	-0.699	77.42	-0.000	-0.724	75.12
25	0.006	0.789	31.85	0.004	0.808	50.26	-0.002	-0.660	73.89	-0.001	-0.674	76.67
26	0.002	0.818	35.74	0.006	0.806	44.19	-0.003	-0.758	78.30	-0.001	-0.720	73.56
27	0.006	0.802	47.93	0.003	0.828	50.83	-0.001	-0.690	73.72	-0.001	-0.749	74.53

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T150724-011

Part No : SST3585S

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs

Test Date: 2015.06.12 ~ 2015.07.24

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
28	0.006	0.789	29.25	0.000	0.782	33.83	-0.002	-0.762	75.63	-0.001	-0.666	73.98
29	0.006	0.796	38.20	0.002	0.779	37.44	-0.003	-0.705	77.88	-0.002	-0.693	75.61
30	0.007	0.802	41.94	0.006	0.794	41.20	-0.002	-0.755	75.39	-0.002	-0.691	75.51
31	0.002	0.809	50.14	0.004	0.804	50.11	-0.003	-0.761	78.21	-0.003	-0.709	73.55
32	0.001	0.826	30.20	0.006	0.785	43.07	-0.001	-0.691	75.57	-0.001	-0.691	77.46
33	0.001	0.788	42.50	0.002	0.812	38.18	-0.002	-0.745	74.80	-0.002	-0.740	78.33
34	0.005	0.824	33.90	0.002	0.786	44.53	-0.001	-0.694	74.95	-0.003	-0.672	74.24
35	0.003	0.816	40.61	0.000	0.812	29.25	-0.003	-0.662	77.34	-0.001	-0.687	74.99
36	0.002	0.818	40.45	0.005	0.826	29.43	-0.002	-0.754	77.86	-0.003	-0.747	75.03
37	0.003	0.827	44.90	0.006	0.795	36.65	-0.001	-0.740	73.58	-0.000	-0.743	77.43
38	0.002	0.804	37.44	0.003	0.804	39.28	-0.003	-0.704	75.40	-0.001	-0.711	75.24
39	0.001	0.826	41.10	0.002	0.780	33.63	-0.002	-0.688	75.98	-0.000	-0.659	76.33
40	0.006	0.808	46.84	0.007	0.804	46.91	-0.002	-0.682	77.06	-0.002	-0.760	74.11
41	0.007	0.803	50.23	0.006	0.790	30.37	-0.001	-0.681	75.67	-0.003	-0.682	74.85
42	0.002	0.830	34.18	0.005	0.779	35.55	-0.001	-0.686	78.34	-0.001	-0.679	75.26
43	0.004	0.818	35.78	0.001	0.811	41.68	-0.001	-0.723	74.09	-0.002	-0.762	76.64
44	0.001	0.778	34.42	0.002	0.821	46.18	-0.003	-0.695	77.59	-0.001	-0.757	75.87
45	0.004	0.808	40.07	0.003	0.797	31.13	-0.000	-0.760	77.74	-0.003	-0.714	74.18
46	0.004	0.811	50.41	0.003	0.819	30.07	-0.000	-0.690	76.52	-0.003	-0.714	78.19
47	0.002	0.794	48.27	0.006	0.782	33.32	-0.000	-0.697	73.78	-0.002	-0.741	76.62
48	0.007	0.825	47.08	0.002	0.804	40.88	-0.002	-0.666	75.75	-0.001	-0.670	76.14
49	0.003	0.787	35.22	0.006	0.819	49.58	-0.002	-0.704	74.84	-0.003	-0.695	76.23
50	0.003	0.794	37.14	0.000	0.807	35.68	-0.003	-0.724	76.48	-0.000	-0.660	77.35
51	0.002	0.825	36.51	0.003	0.815	51.69	-0.001	-0.706	76.99	-0.002	-0.715	77.00
52	0.003	0.784	33.17	0.007	0.810	38.28	-0.001	-0.729	77.57	-0.002	-0.699	73.99
53	0.003	0.820	33.19	0.001	0.827	51.39	-0.002	-0.681	77.00	-0.000	-0.737	75.52
54	0.006	0.822	35.01	0.002	0.829	30.80	-0.001	-0.675	73.82	-0.003	-0.679	78.33

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T150724-011

Part No : SST3585S

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs

Test Date: 2015.06.12 ~ 2015.07.24

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
55	0.003	0.785	44.96	0.001	0.815	33.20	-0.002	-0.666	74.92	-0.002	-0.741	73.62
56	0.003	0.796	45.12	0.001	0.811	36.43	-0.001	-0.680	77.42	-0.001	-0.727	74.77
57	0.001	0.787	42.27	0.001	0.828	41.92	-0.001	-0.738	77.66	-0.002	-0.757	78.41
58	0.001	0.817	44.94	0.003	0.830	41.03	-0.002	-0.705	75.87	-0.001	-0.747	76.90
59	0.005	0.781	45.82	0.004	0.825	39.25	-0.002	-0.682	78.09	-0.001	-0.734	75.40
60	0.002	0.813	49.34	0.006	0.788	47.23	-0.001	-0.679	75.15	-0.002	-0.667	76.55
61	0.005	0.816	31.73	0.001	0.778	32.76	-0.002	-0.749	75.69	-0.002	-0.747	74.45
62	0.001	0.799	41.93	0.004	0.804	36.54	-0.002	-0.699	78.14	-0.002	-0.697	77.03
63	0.005	0.782	41.74	0.004	0.805	38.28	-0.002	-0.688	76.97	-0.001	-0.680	78.58
64	0.005	0.795	44.90	0.000	0.826	36.85	-0.002	-0.687	76.63	-0.003	-0.692	75.70
65	0.007	0.823	51.66	0.003	0.787	38.02	-0.002	-0.716	78.58	-0.000	-0.716	76.20
66	0.000	0.789	32.25	0.004	0.816	36.51	-0.003	-0.673	74.56	-0.001	-0.663	77.01
67	0.004	0.825	33.89	0.006	0.828	39.59	-0.000	-0.689	78.36	-0.000	-0.759	76.02
68	0.007	0.805	41.98	0.006	0.804	43.15	-0.001	-0.752	74.81	-0.001	-0.715	74.37
69	0.006	0.821	40.00	0.003	0.790	42.18	-0.000	-0.758	77.15	-0.001	-0.736	75.12
70	0.006	0.829	46.53	0.002	0.830	47.75	-0.002	-0.667	78.52	-0.000	-0.756	77.21
71	0.005	0.781	46.19	0.001	0.783	47.74	-0.001	-0.718	75.06	-0.002	-0.750	78.33
72	0.001	0.793	30.95	0.005	0.812	28.71	-0.001	-0.685	76.95	-0.001	-0.750	75.29
73	0.006	0.827	47.13	0.004	0.818	28.78	-0.002	-0.698	77.34	-0.002	-0.739	77.34
74	0.007	0.788	47.97	0.003	0.781	51.47	-0.001	-0.662	76.15	-0.001	-0.679	77.87
75	0.002	0.820	37.35	0.001	0.790	36.67	-0.001	-0.763	74.84	-0.000	-0.739	73.54
76	0.003	0.779	40.47	0.001	0.780	33.70	-0.001	-0.732	76.87	-0.001	-0.659	76.41
77	0.004	0.823	32.60	0.002	0.781	41.72	-0.001	-0.718	76.74	-0.002	-0.684	77.36

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Solderability Test Data

Report No : T150724-011
Part No : SST3585S
Test Equipment: JUNO Test System DTS-1000
Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)
Test Condition: 245℃ ± 5℃, 5Sec
Test Date: 2015.07.24
Test Standard : JESD22 STANDER Method-B102
Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
1	0.005	0.812	37.58	0.003	0.824	44.07	-0.002	-0.732	73.63	-0.001	-0.682	75.92
2	0.002	0.801	32.09	0.006	0.797	36.80	-0.001	-0.685	75.72	-0.003	-0.659	76.20
3	0.005	0.816	37.75	0.002	0.801	39.45	-0.001	-0.751	74.53	-0.001	-0.734	75.38
4	0.006	0.780	29.97	0.006	0.825	33.02	-0.002	-0.755	76.41	-0.000	-0.690	75.73
5	0.006	0.789	39.60	0.004	0.814	44.56	-0.001	-0.667	73.65	-0.001	-0.674	75.26
6	0.006	0.797	28.67	0.001	0.798	40.70	-0.000	-0.753	78.11	-0.001	-0.675	77.29
7	0.000	0.813	41.65	0.003	0.792	34.86	-0.002	-0.742	77.49	-0.002	-0.739	77.83
8	0.005	0.780	30.69	0.002	0.797	38.79	-0.000	-0.731	78.23	-0.002	-0.690	77.18
9	0.006	0.816	50.96	0.006	0.797	28.99	-0.002	-0.699	76.95	-0.002	-0.723	78.44
10	0.005	0.826	34.33	0.000	0.809	32.49	-0.003	-0.722	73.87	-0.001	-0.671	77.42

Made By: King Huang Approval: Peter Yang